

Notice of References Cited

Application/Control No.

09/852,899

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

2814

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	T. Hamamoto et al., Trench-Trench Leakage Current Characteristics in the Stacked Trench Capacitor (STT) Cell. IEEE 1991, pp. 419-422.
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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